

Apport de l'ICP MS a haute resolution et en temps de vol pour l'analyse de nanoparticules

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high-performance mass spectrometers. Our highly specialised instrumentation includes; <u>Multi-Collector ICP-MS</u> (MC-ICP-MS), <u>Time-of-Flight ICP-MS</u> (TOF-ICP-MS), <u>High Resolution ICP-</u> <u>MS</u> (HR-ICP-MS), <u>Glow Discharge Mass Spectrometry</u> (GD-MS), <u>Isotope Ratio Mass Spectrometry</u> (IRMS), <u>Gas Analysis Mass</u> <u>Spectrometry</u>, <u>Thermal Ionisation Mass Spectrometry</u> (TIMS).





Introduction

AttoM ES

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The AttoM ES HR-ICP-MS is a **double-focusing single-collector instrument** of forward Nier-Johnson geometry which features the unique FastScan Ion Optics.

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The instrument is entirely purpose designed and built to provide the best performance and reliability coupled with flexibility and ease-of-use for precise and accurate **elemental and isotope ratio analysis**.

AttoM ES is an instrument of choice for Earth Sciences, Environmental Science, Nuclear Research, Archaeology, Forensics, Nanoparticle characterisation...



² Co-funded by the Horizon 2020 Framework Programme of the European Union under the grant N° 952306



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Resolution (source slit)

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Attom uses fixed width slits for resolution

Default resolutions are: 300, 2500, 4000, 10000 and >10000 (not specified)

Slits positions are 12 for source and 5 for collector

Source: LR 500, MR 40, HR 10 and UR 6 μ m



Forward Nier-Johnson geometry



High Resolution

- To be able to deal with interferences, two major modes of operations in the ICP-MS world:
- Improve the signal to background ratios using collision/reaction cell technology with analyte/interference shifts, energy transfers and losses
- Using the exact mass difference between analyte and interference for physical separation using high resolution





High Resolution



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High Resolution





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Deflector Ion Optics:

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- Pair of quadrupoles for beam shaping
- Two sets of parallel plates, before and after magnet

Able to deflect the incoming ion beam into magnetic field so that ions take a different path, effectively changing the radius inside the field.







Analysis method



Measure on the centre of the peak (due to flat top peak). 10µs timeslots



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Scan a mass window around the peak centre 100µs timeslots





R=4000 or R=10 000



R=300

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Deflector jump (LR)



With no deflection

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only the magnetic field dictates which m/z goes to the detector



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Deflector jump (LR)



Fixed magnetic field but voltages applied to the deflectors:

lon beam deflected, different m/z are detected..







Deflector jump (LR)







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AttoM ES for nanoparticle analysis applications









Main features







Nanoparticles analysis with AttoM – HR-ICP-MS NU

Dwell time > 10 μs Continously (no settling time)





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<u>Dwell time > 10 μs</u> <u>Continously (no</u> settling time)

Why do we want to use a short dwell time ?

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Adapted from Strenge et al

Arrival of the ion cloud on the detector = $300-400 \ \mu s$

1 ms (dwell time)







<u>Dwell time > 10 μs</u> <u>Continously (no</u> settling time)

Why do we want to use a short dwell time ?



Arrival of the ion cloud on the detector = 300-400 μs

40 µs (dwell time)





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<u>Dwell time > 10 μs</u> <u>Continously (no</u> <u>settling time)</u>

Why do we want to use a short dwell time ?

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Improvment of detection limit



High sensitivity

- The interface region between the sampler and skimmer cones is pumped using an (earthed)
 50 m3h-1 rotary pump, to give a working pressure in this region of <1 mbar.
- The Enhanced Sensitivity interface provides **very high efficiency** for dry sample introduction systems whilst not compromising performance for normal "wet" sample introduction systems.



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Signal example Au **5nm** (Aridus, 40 µs dwell time)

Detection limit with desolvator (Aridus, CETAC):

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- Au : 4.5 nm
- Ag : 4.5 nm
- CeO :4 nm





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Flexible data processing software



The software NuQuant is designed to easily handle nanoparticles measurement :

• Automatic peak search and adjustable peak width



Smoothing of the data and research of the peak maxima and minima with criteria that allow different:

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- Peak size,
- Peak widths
- Partially merged peaks
- Continuous background signals to be distinguished easily





Flexible data processing software



The software NuQuant is designed to easily handle nanoparticles measurement:

- Automatic peak search and adjustable peak width •
- Ready to use script to detect and measure nanoparticle size ٠ distribution, concentration, ionic background...



Possibility to use different calibration methods:

- Ionic standard
- Nanoparticle standard



Nanoparticles analysis with AttoM – HR-ICP-MS



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Flexible data processing software



The software NuQuant is designed to easily handle nanoparticles measurement :

- Automatic peak search and adjustable peak width
- Ready to use scripts to detect and measure nanoparticle size distribution, concentration, ionic background...
- Possibility for the user to access the scripts to read / modify / create them. Calculations are <u>transparents</u>





Nanoparticles analysis with AttoM – HR-ICP-MS \mathcal{NU}





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NP applications





 In classical mode (ionic solution measurement), use of desolvator improve sensitivity by factor ~ 10

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Transport efficiency

Desolvator useful for SP-ICP-MS ?



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Comparison of calibrations for wet and dry plasma



1 ppb Au



4-7 nm / 10 nm Au NP solutions

	lonic sensitivity, cps/ppt	Sample transport rate, μL/sec
Wet sample introduction, standard cones	330	0.124
Dry Aridus II, ES interface	3180	0.434
Enhancement	9.6	3.5
		•••••

Improvement in ion transport expected : ~2.7.





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Comparison of number of counts per particle for DRY and WET



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Comparison of number of counts per particle for DRY and WET



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Particle count distributions for 10nm standard using wet and dry sample introduction systems







Comparison of detection limits for DRY and WET

Wet – nominal 10nm Au 27 counts



Wet: 6 nm

Dry – nominal 10nm Au 76 counts

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Detection limits based on baseline plus 3 SD noise:



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Dry: **4** nm



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 Some elements have degraded detection limits in ICP-MS due to interferences at the mass of interest from molecular species found in the plasma

Example of ⁵⁶Fe interfered by ⁴⁰Ar¹⁶O





 Some elements have degraded detection limits in ICP-MS due to interferences at the mass of interest from molecular species found in the plasma

Example of ⁵⁶Fe interfered by ⁴⁰Ar¹⁶O

Disadvantage of using higher resolution

- Loss of transmission
- Loss of the flat peak





Resolution 4000







 Some elements have degraded detection limits in ICP-MS due to interferences at the mass of interest from molecular species found in the plasma

Example of ⁵⁶Fe interfered by ⁴⁰Ar¹⁶O



- Source slit narrowed (4000)
- Collector slit left wide open (300)









 Some elements have degraded detection limits in ICP-MS due to interferences at the mass of interest from molecular species found in the plasma

Example of ⁵⁶Fe interfered by ⁴⁰Ar¹⁶O



- Source slit narrowed (4000)
- Collector slit left wide open (300)











Measure of 30 nm Fe3O2 nanoparticles









Analysis of : Np 15 nm Au in ionic background (10 ppt, 100 ppt, 1 ppb)

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Improvements in single particle analysis using a time-of-flight mass analyzer

Vitesse TOF-ICP-MS





ICP-TOF-MS Principle

push out Detector region counts m/z 5. Full spectra recorded <30 µs Flight tube time of flight quadrupole Full mass Single isotope spectrum Slower Fast acquisition acquisition (1-2

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(50-100 µs)

Reflectron



1. Incoming flow of ions

2. Extraction of ion packets

4. Ions travel thought the fly

in the push out region

3. Acceleration of the ions with equal energy

tube with a speed

depending on m/zlighter ions

heavier ions

from ICP

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Single Particle Analysis – Acquisition Speed



A high time resolution is crucial to most accurately measure the single bursts of signals







Single Particle Analysis – Multi Element Capability

 Quadrupole: No multielement information obtainable

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- Elemental composition of entire population in multiple mea







Single Particle Analysis – Multi Element Capability

 Vitesse: Full elemental information for every event detected

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- Analysis on a per particle basi



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Single Particle Analysis Example nu

Mixture of Au core Ag shell and pure Au NPs







Single Particle Analysis Example



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Mixture of Au core Ag shell and pure Au NPs







Single Particle Analysis Example

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- Various types of NPs:
 - FeCoZn, FeCoNi, Au, Ag, AuAg, Natural NPs







Single Particle Analysis Example

- Various types of NPs:
 - FeCoZn, FeCoNi, Au, Ag, AuAg, natural clay NPs

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Single Particle Analysis

• Various types of NPs:

– FeCoZn, FeCoNi, Au, Ag, AuAg



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Single Particle Analysis Uses

- "Single particle" analysis finally truly possible
- Fast quality assurance of multi element nanoparticles after production
- Nanoparticle analysis downstream of erosion events
- Discrimination of man made and natural nanoparticles
 - Man made are usually pure, single element nanoparticles
 - Natural nanoparticles are usually due to erosion and hence contain multiple elements



